

FORM PTO-1449 (SUBSTITUTE) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT-BY-APPLICANT (37 CFR 1.98(b))				Attorney Docket No.: MUH-12757 Appl. No.: Applicant: MATTHIAS KROENKE ET AL. Filing Date: September 23, 2003 Group Art Unit:																																																																																			
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